

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application	)	<u>PATENT APPLICATION</u>
	)	
Inventors: Frederick Ware, et al.	)	
	)	
Application No.: 10/768,443	)	Art Unit: 2829
	)	
Filed Date: Jan. 30, 2004	)	Examiner: Nguyen, T.
	)	
Title: METHOD AND APPARATUS FOR TEST	)	Customer No.: 38456
CHARACTERIZATION OF SEMICONDUCTOR	)	
COMPONENTS	)	
	)	

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RESPONSE TO OFFICE ACTION UNDER 37 C.F.R. §1.111

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

This RESPONSE is in reply to the outstanding Office action.

**AMENDMENTS to the CLAIMS** begin on Page 2 of this RESPONSE.

**REMARKS** begin on Page 28 of this RESPONSE.